

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L3	1	("20040227187").PN.	US-PGPUB; USPAT; USOCR	OR	OFF	2005/10/26 17:09
L4	1	("20040253792").PN.	US-PGPUB; USPAT; USOCR	OR	OFF	2005/10/26 17:27
L5	1	("20040208454").PN.	US-PGPUB; USPAT; USOCR	OR	OFF	2005/10/26 17:56
L6	1	("6475869").PN.	US-PGPUB; USPAT; USOCR	OR	OFF	2005/10/26 17:56
L8	2	(US-20050224786-\$ or US-20050230763-\$).did.	US-PGPUB	OR	OFF	2005/10/26 18:39
L9	2	8 and doped adj (layer region)	US-PGPUB; USPAT; EPO; DERWENT; IBM_TDB	OR	ON	2005/10/26 18:36
L11	143	sige adj channel	US-PGPUB; USPAT; USOCR	OR	OFF	2005/10/26 18:40
L12	1265	(257/18,19,27,192).CCLS.	US-PGPUB; USPAT; USOCR	OR	OFF	2005/10/26 18:41
S1	1	("20050230763").PN.	US-PGPUB; USPAT; USOCR	OR	OFF	2005/10/26 09:45
S2	1	S1 and substrate and diamond and strained adj silicon	US-PGPUB; USPAT; EPO; DERWENT; IBM_TDB	OR	OFF	2005/10/26 10:52
S3	1616485	Yeo selvakumar wu nayak lu	US-PGPUB; USPAT; EPO; DERWENT; IBM_TDB	OR	OFF	2005/10/26 10:52
S4	70	S3 and strained near3 gate	US-PGPUB; USPAT; EPO; DERWENT; IBM_TDB	OR	OFF	2005/10/26 10:58
S5	117	S3 and strained with gate	US-PGPUB; USPAT; EPO; DERWENT; IBM_TDB	OR	OFF	2005/10/26 10:53

S7	2	((("6583000") or ("6600170")).PN.	US-PGPUB; USPAT; USOCR	OR	OFF	2005/10/26 16:47
S10	5	taiwan adj semiconductor and sill	US-PGPUB; USPAT; EPO; JPO	OR	ON	2005/10/26 11:21